

Notice of References Cited	Application/Control No. 09/913,014	Applicant(s)/Patent Under Reexamination FAN ET AL.	
	Examiner Lynne Edmondson	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,431,324	07-1995	Kajiwara et al.	228/1.1
*	B	US-6,323,943	11-2001	Maruyama et al.	356/28.5
*	C	US-5,734,108	03-1998	Walker et al.	73/650
*	D	US-6,181,431	01-2001	Siu, Bernard	356/502
*	E	US-4,854,494	08-1989	von Raben, Klaus-Ulrich	228/1.1
*	F	US-6,424,407	07-2002	Kinrot et al.	345/166
*	G	US-6,285,514	09-2001	O'Meara et al.	359/721
*	H	US-6,392,692	05-2002	Monroe, David A.	348/143
*	I	US-5,623,307	04-1997	Kotidis et al.	356/493
*	J	US-5,431,324	07-1995	Kajiwara et al.	228/102
	K	US-3,800,893	04-1974	Ramsay et al.	177/25.14
	L	US-6,279,248	08-2001	Walters, Gary W.	33/784
	M	US-5,199,630	04-1993	Felber et al.	228/102

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 01/73373-A1	10-2001	WIPO	Vikhagen	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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